

CLAIMS

WHAT IS CLAIMED IS:

1. A semiconductor integrated circuit comprising:

a power-on resetting circuit for activating a reset signal which initializes an internal circuit, for a predetermined period after a power supply is switched on, and then inactivating the reset signal; and

a timing changing circuit for changing an inactivation timing of said reset signal.

2. The semiconductor integrated circuit according to claim 1, wherein said timing changing circuit changes said inactivation timing corresponding to a threshold voltage of transistors implemented in said internal circuit.

3. The semiconductor integrated circuit according to claim 1, further comprising a voltage generator for generating an internal supply voltage in accordance with an external supply voltage, and wherein

said timing changing circuit changes said inactivation timing corresponding to said internal supply voltage which varies with a threshold voltage of transistors implemented in said voltage generator.

4. The semiconductor integrated circuit according to claim 3, wherein said timing changing circuit comprises a programming circuit having a fuse for changing said inactivation timing by programming the fuse corresponding to a level of said internal supply voltage.

5. The semiconductor integrated circuit according to claim 4, further comprising a testing circuit for changing said internal supply voltage to determine said fuse to be programmed for the sake of optimizing said inactivation timing.

6. The semiconductor integrated circuit according to claim 4, wherein said internal supply voltage is adjusted to a predetermined value simultaneously with the change of

said inactivation timing, by programming said fuse.

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